

Fig. 1

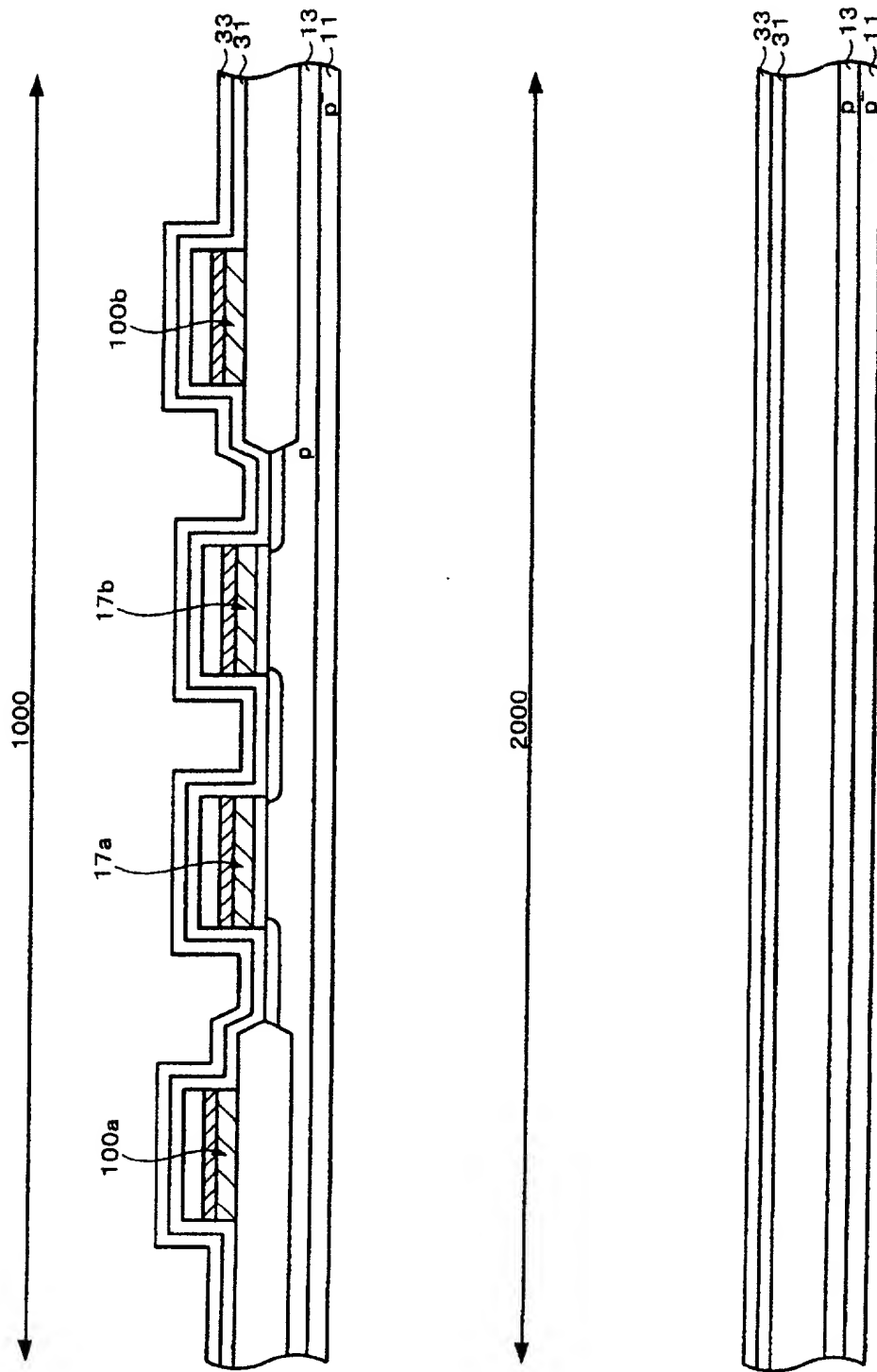


Fig. 3

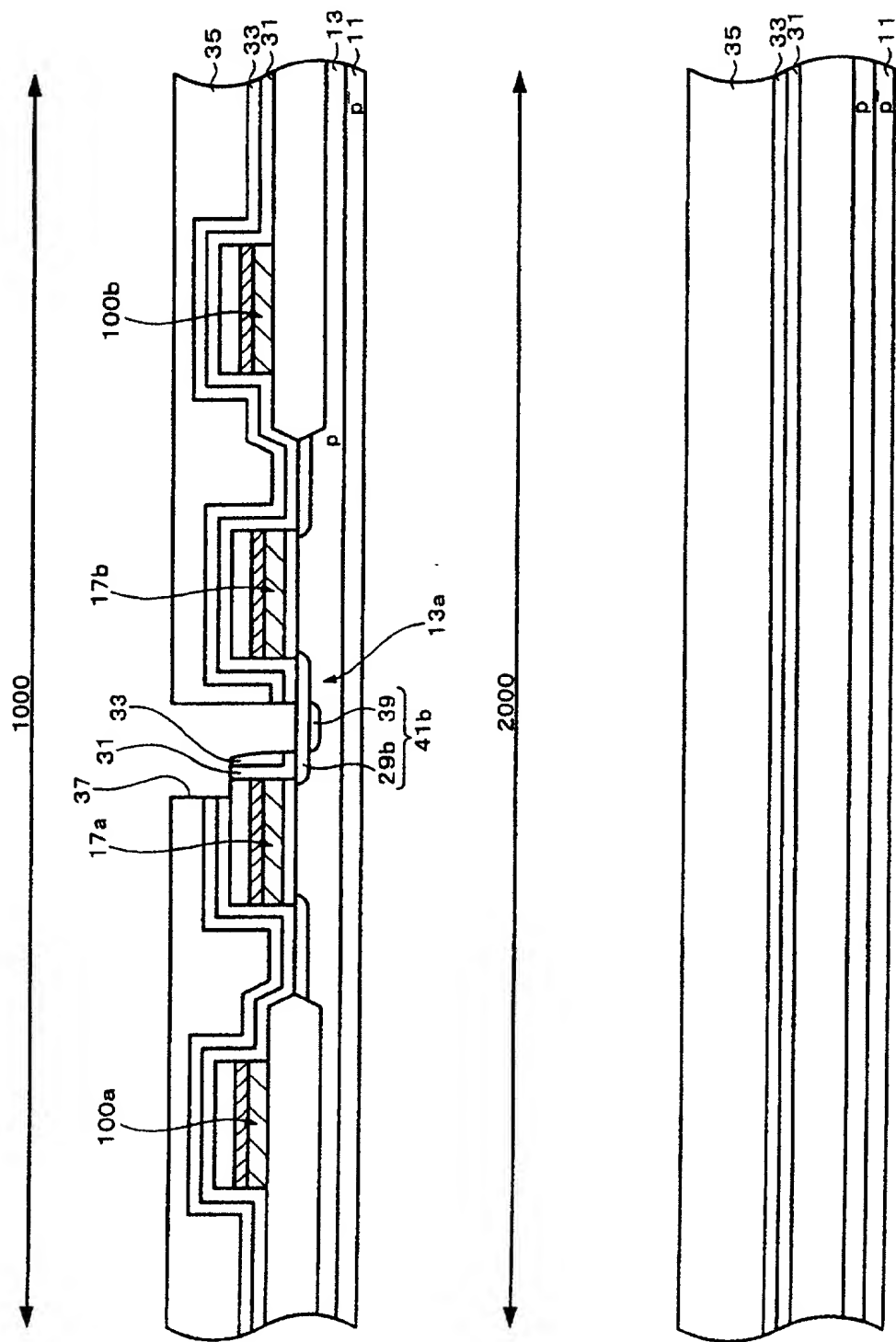


Fig. 4

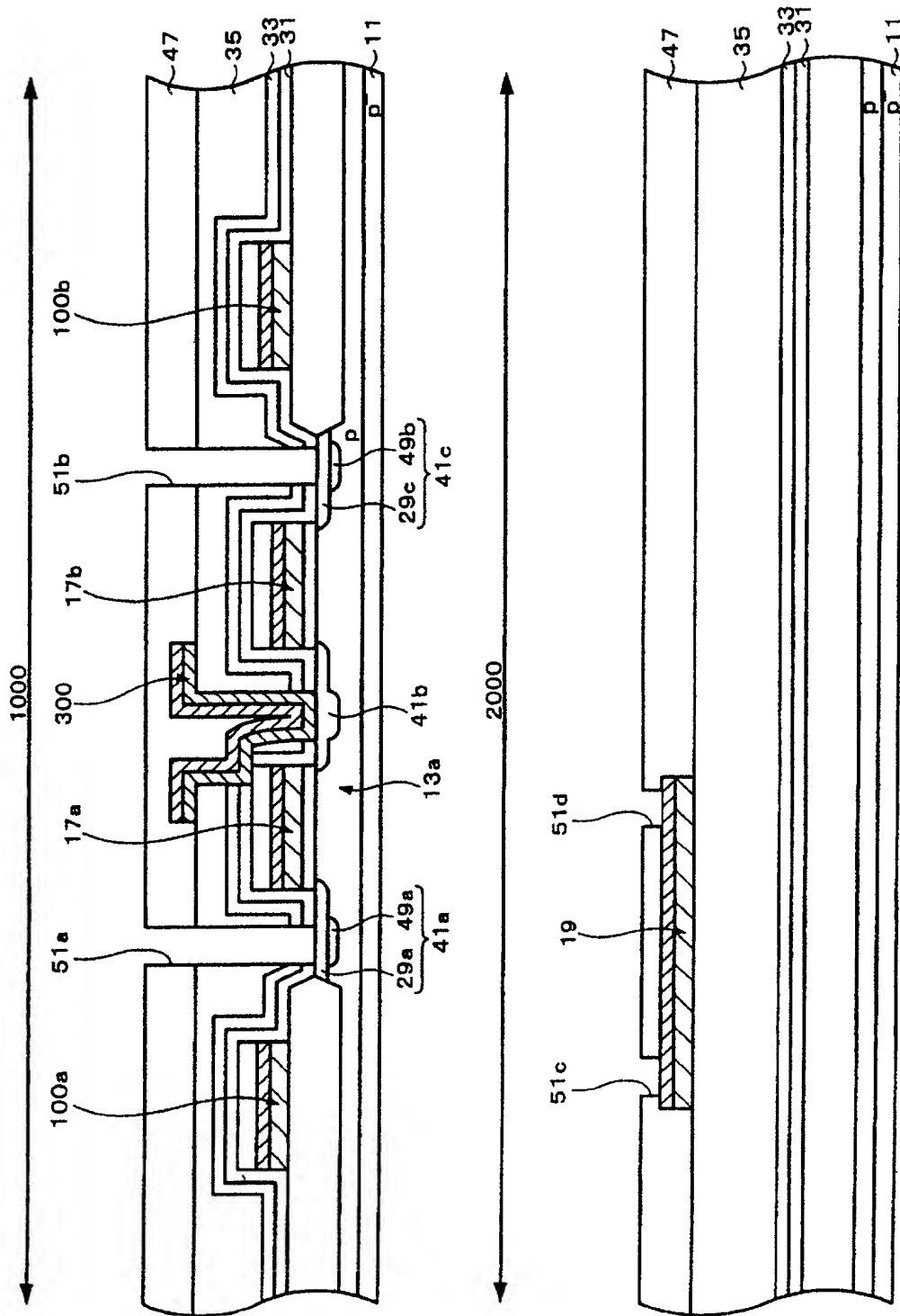


Fig. 6

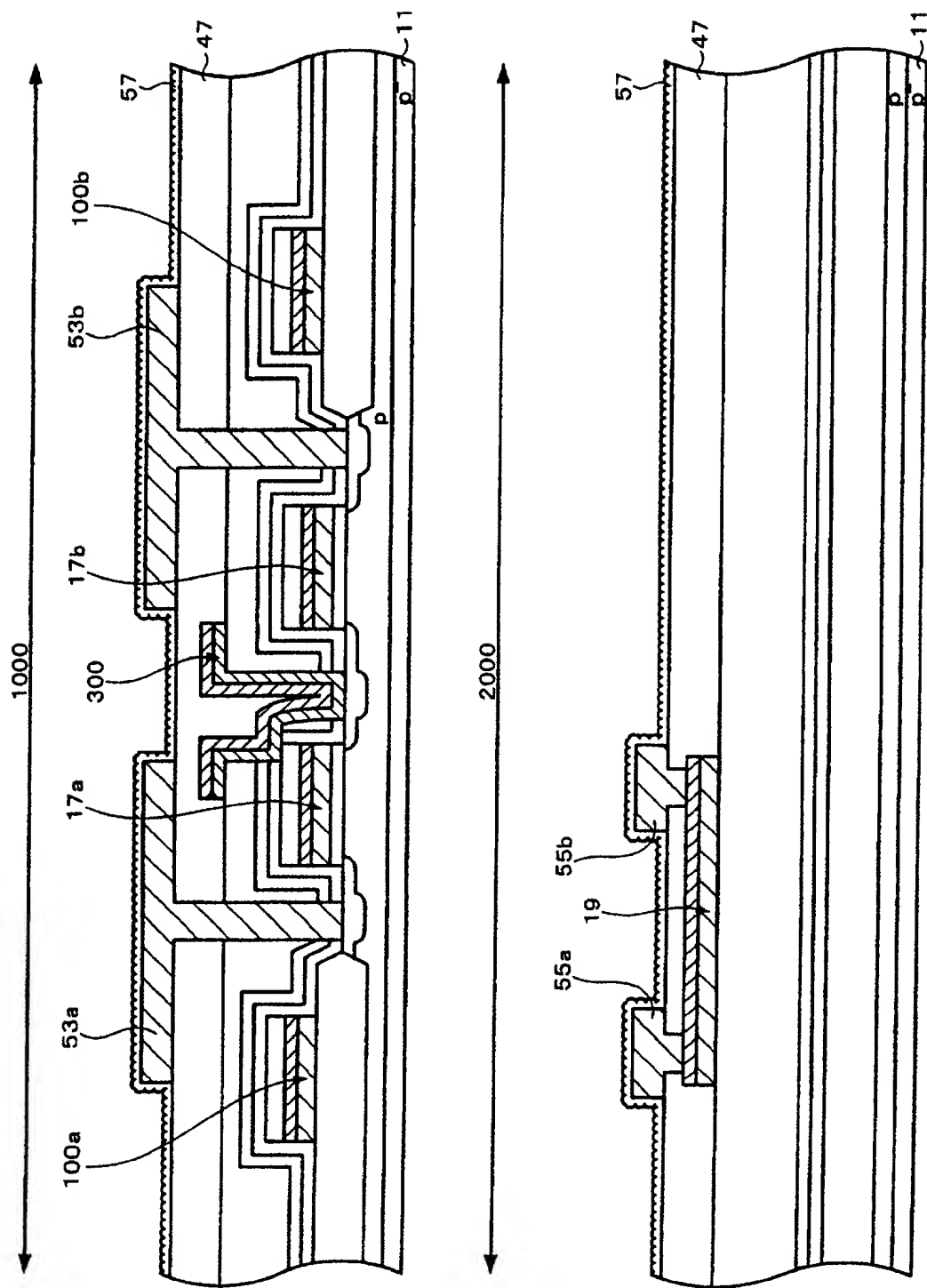


Fig. 8

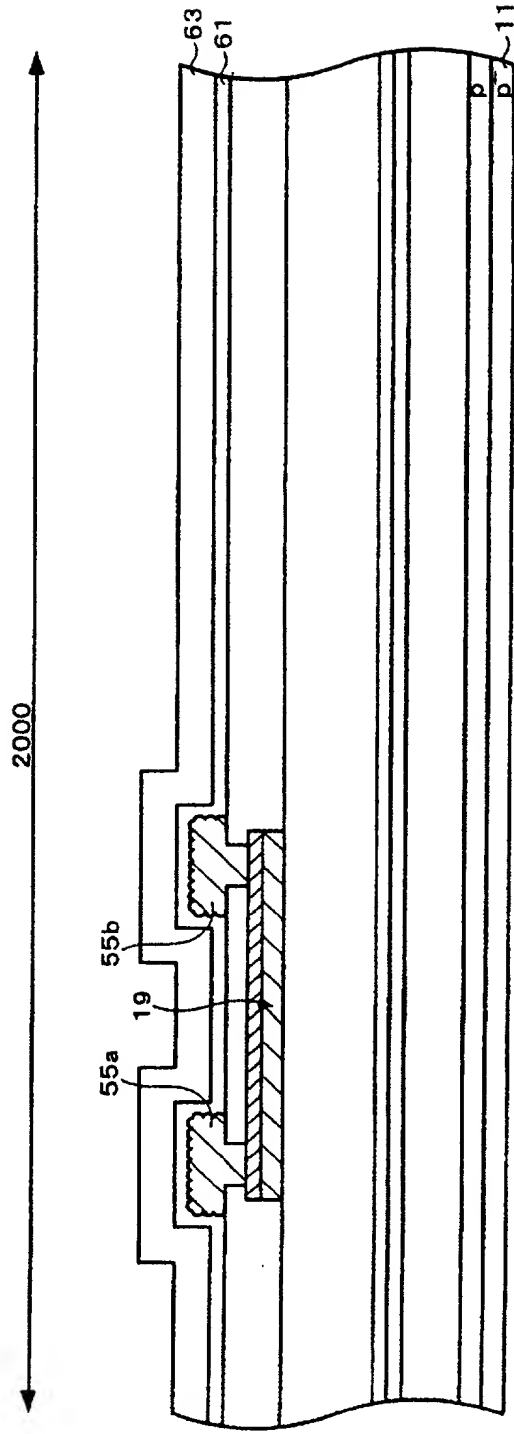
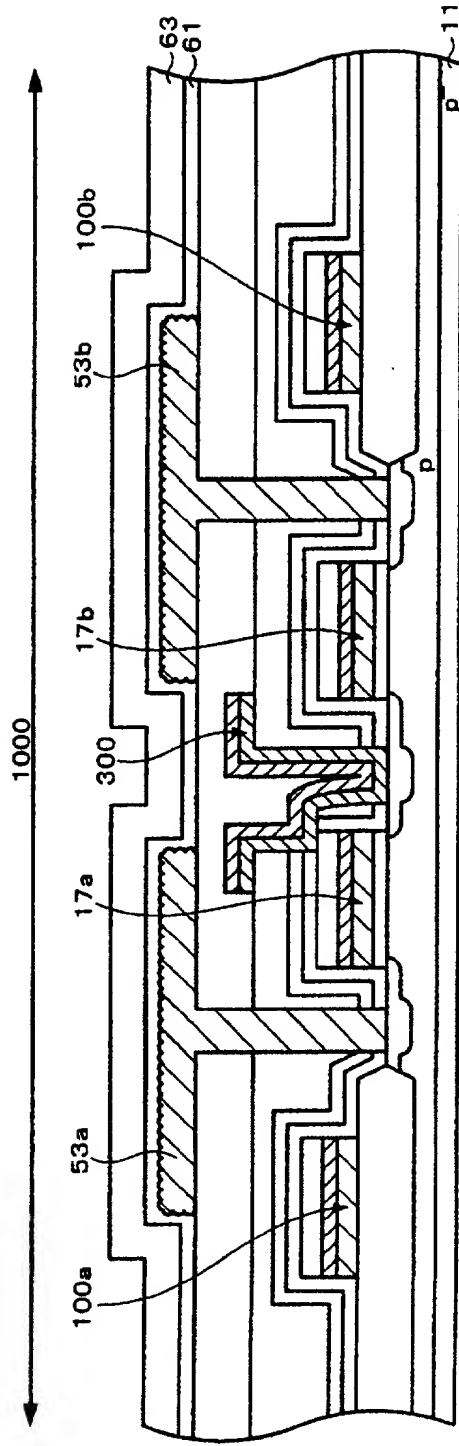


Fig. 11

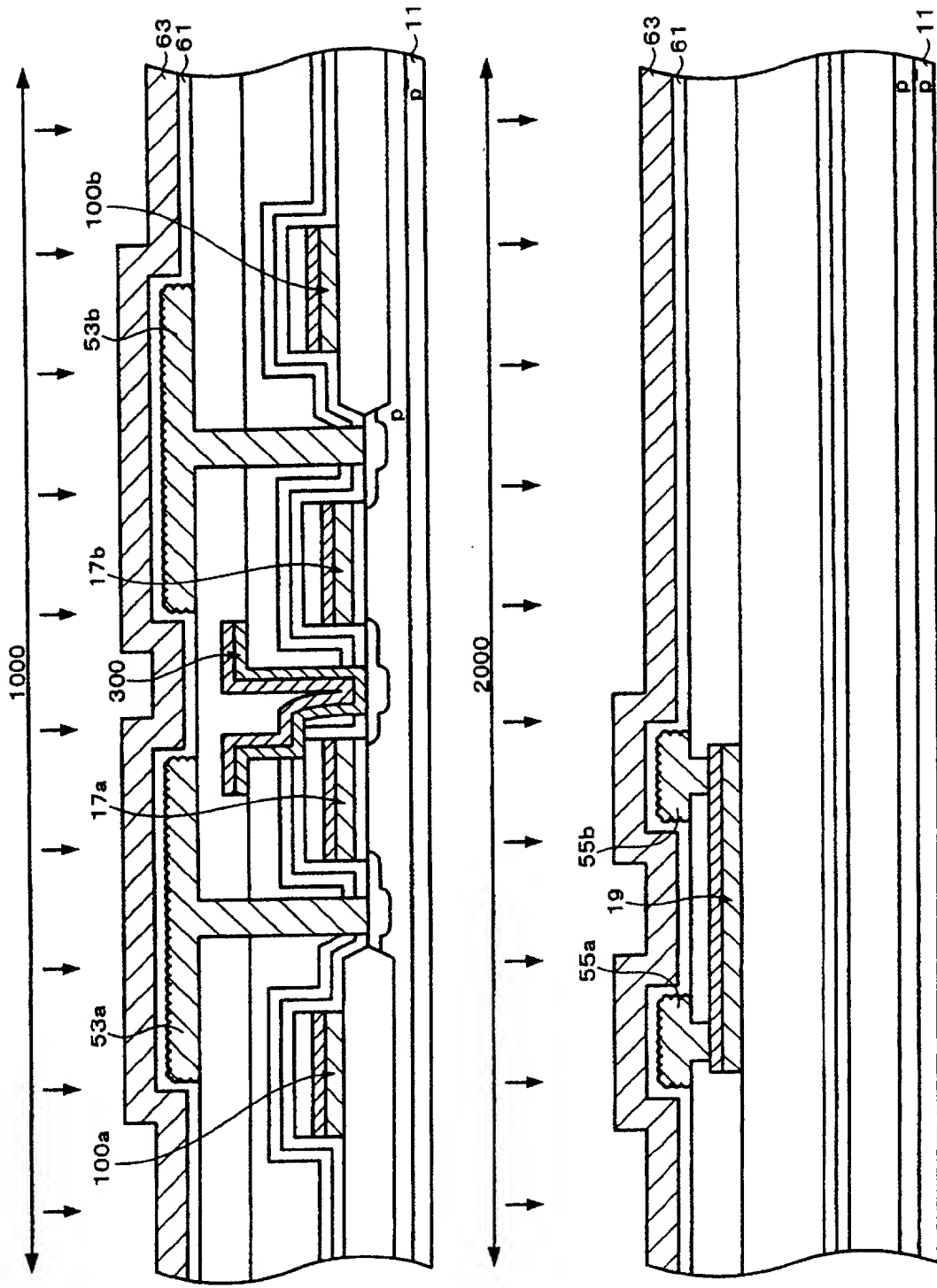


Fig. 12

FIG. 13 is a cross-sectional view of a semiconductor device in accordance with the present invention, showing a top view of the device.

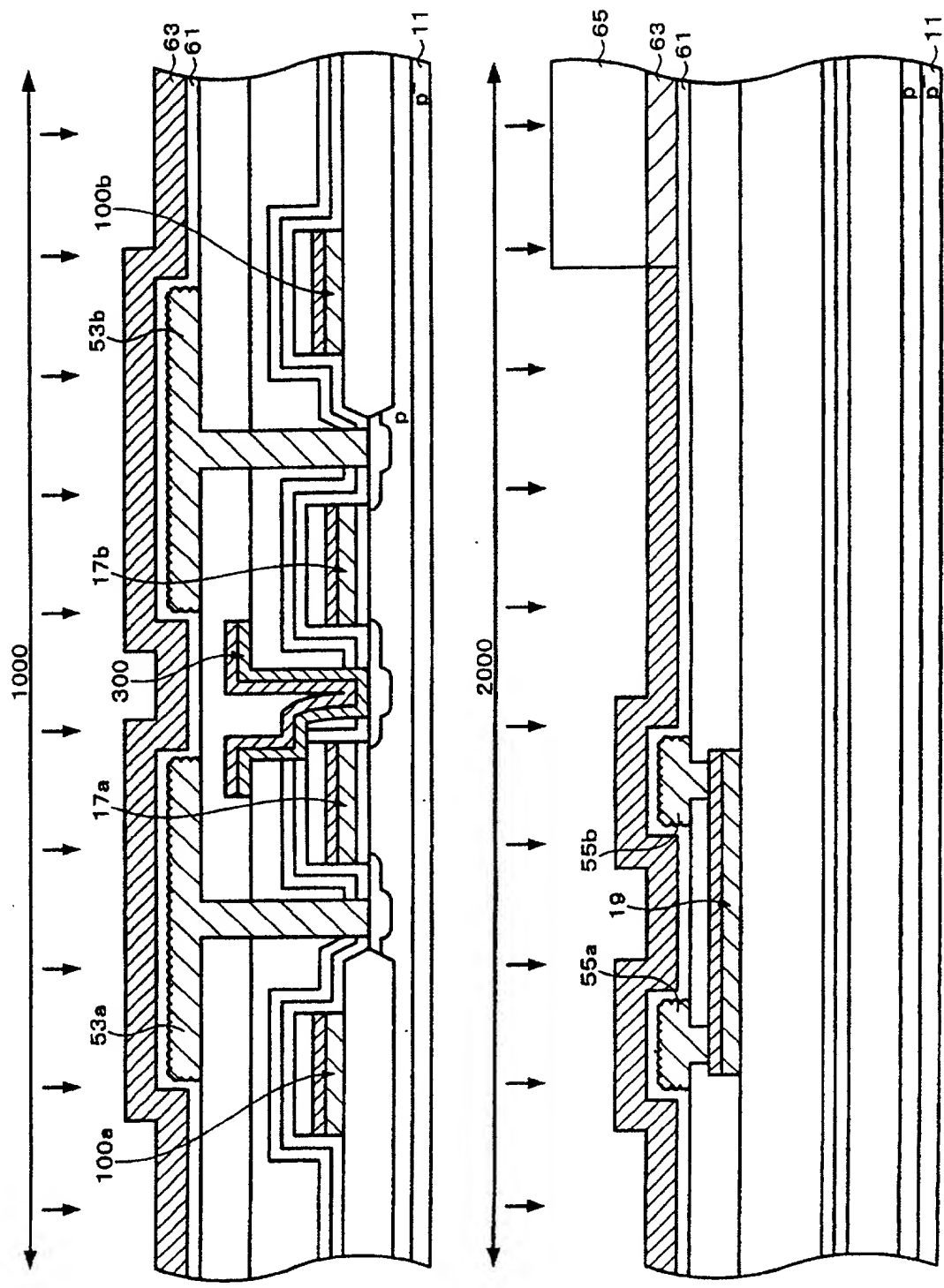


Fig. 13

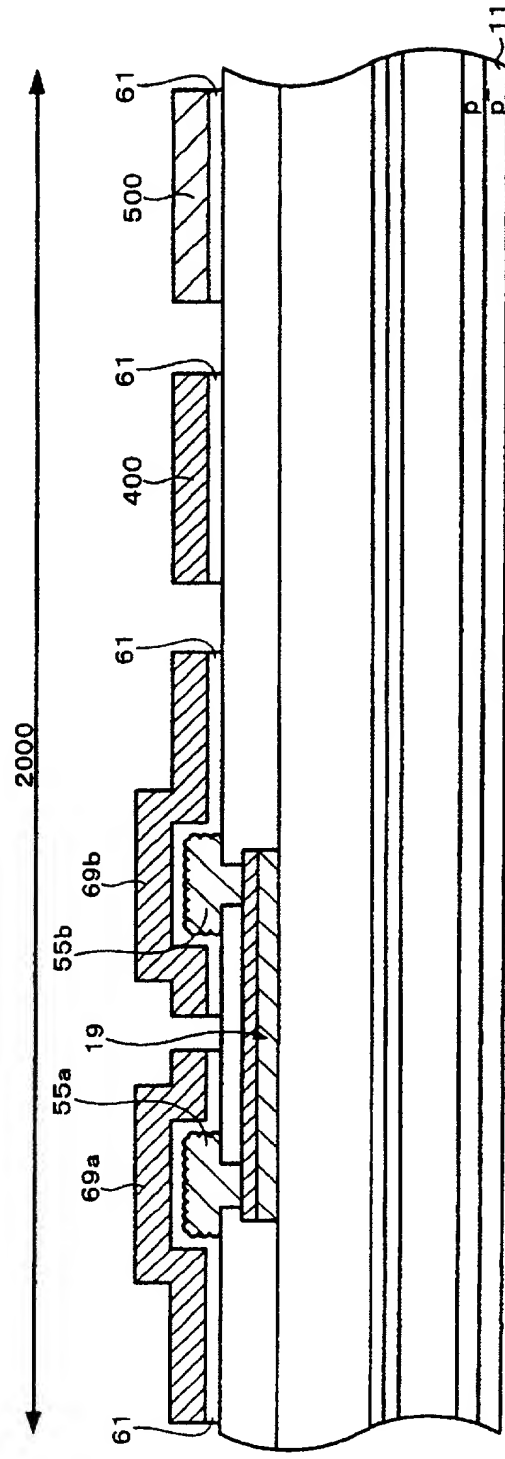
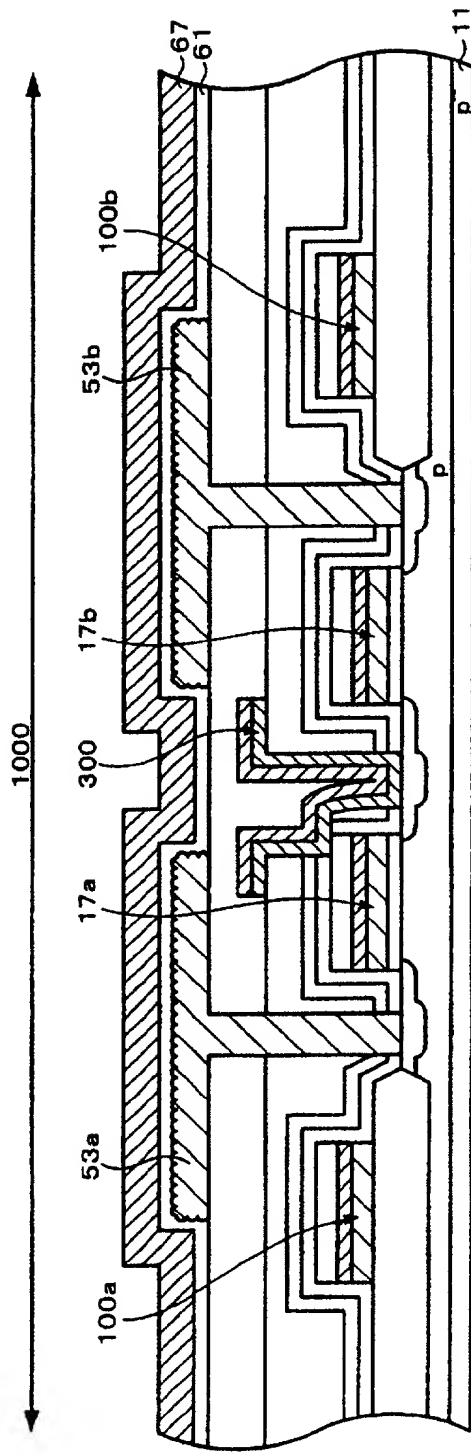
[illegible]

Fig. 14

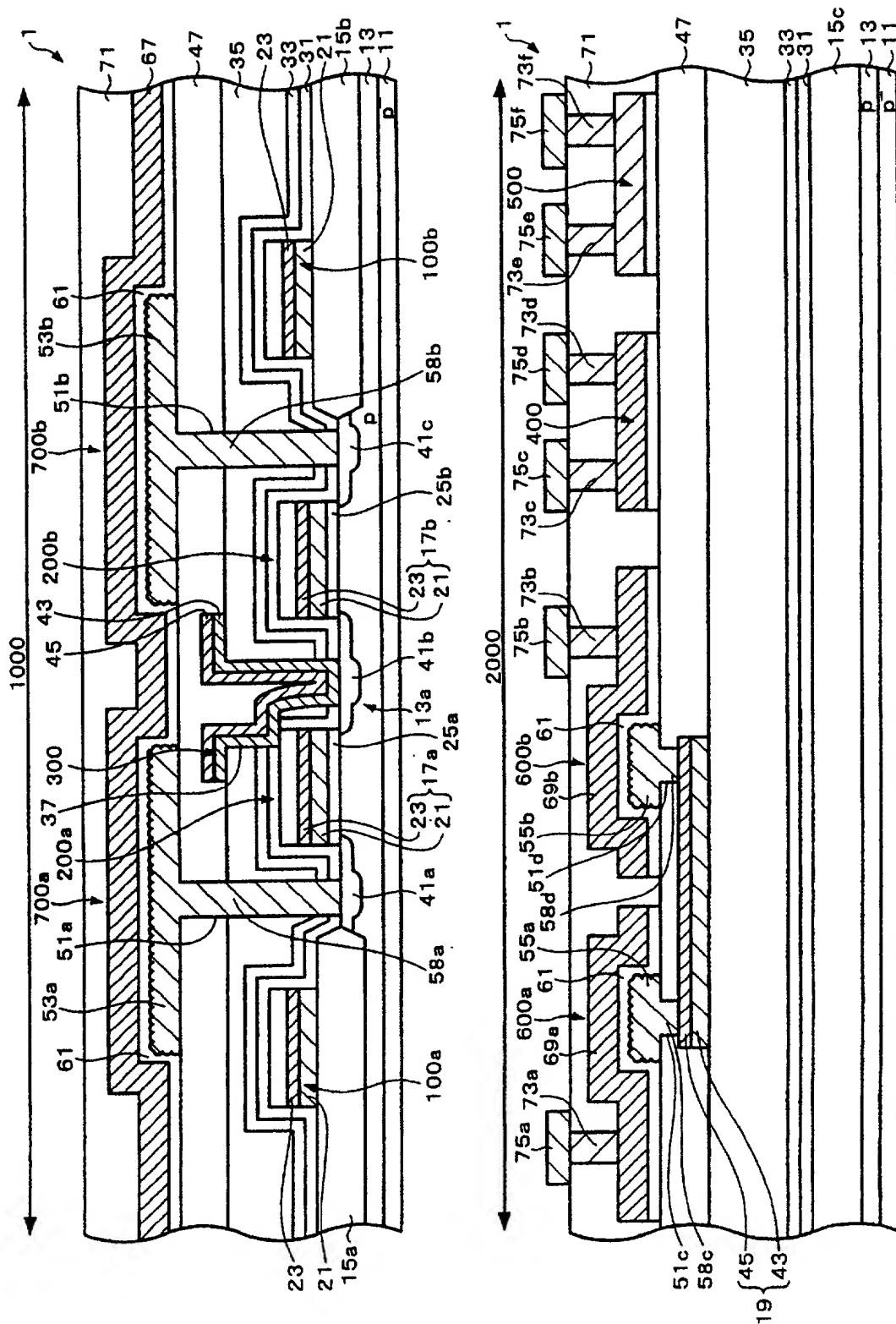


Fig. 15

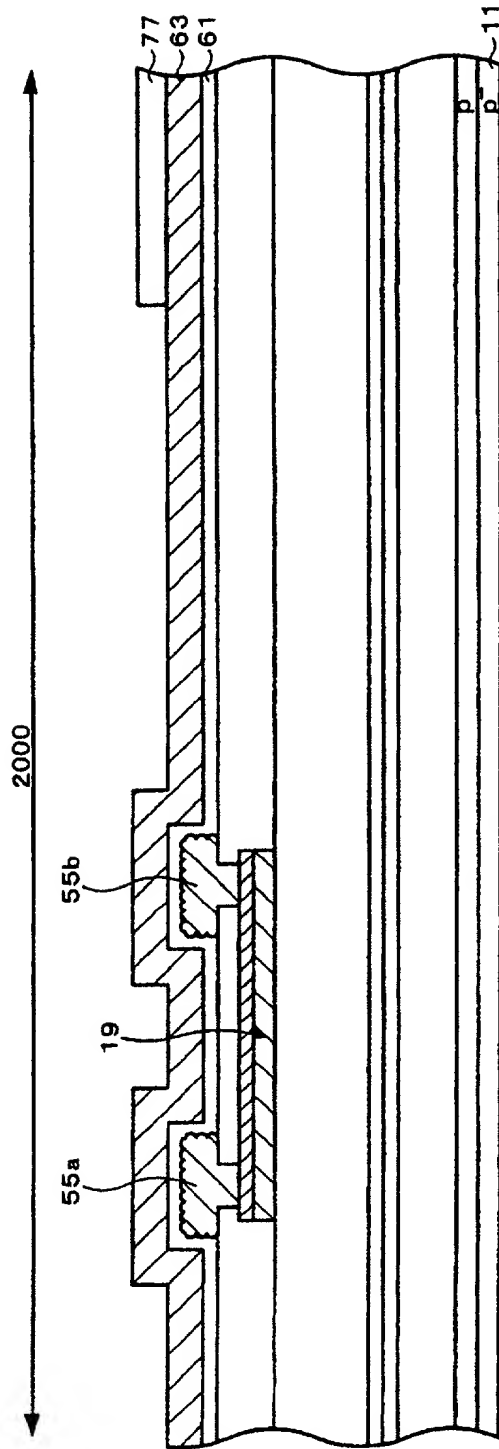
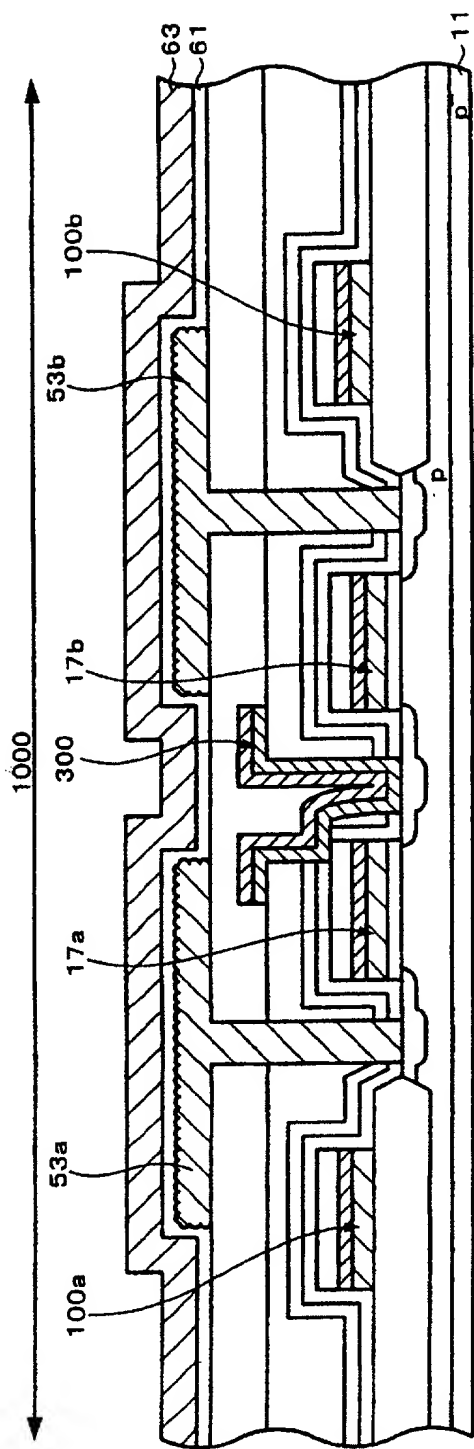


Fig. 16

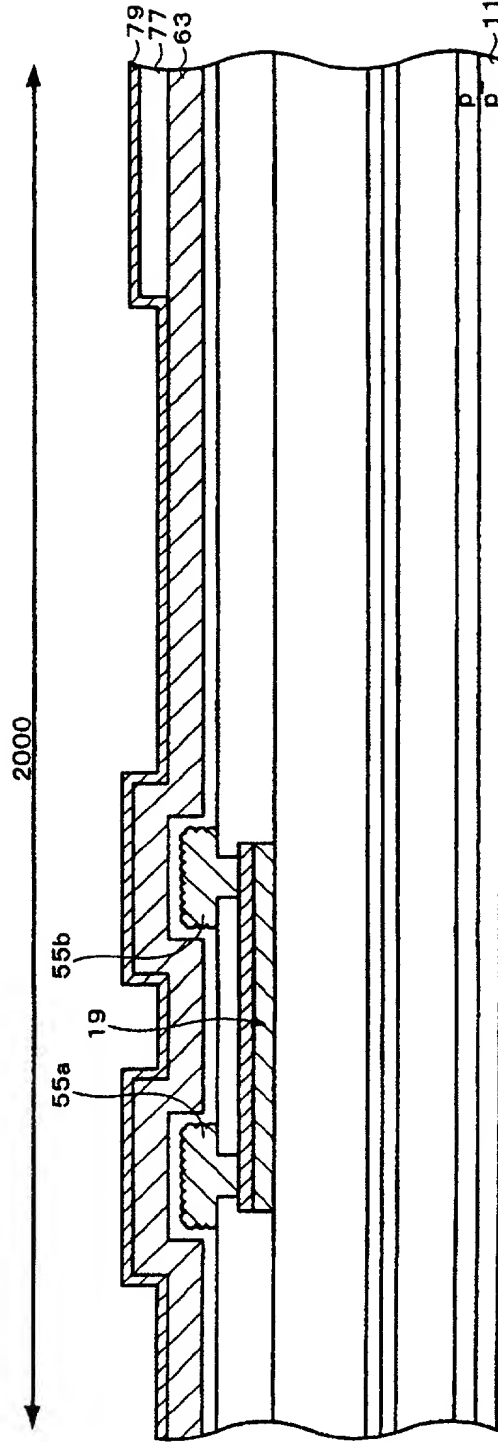
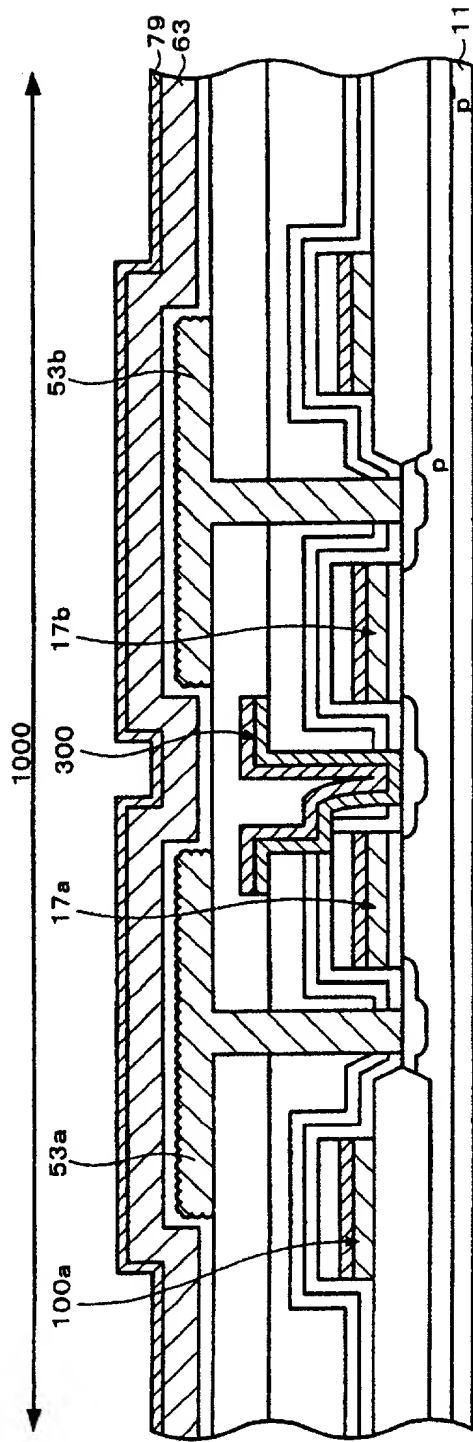


Fig. 19

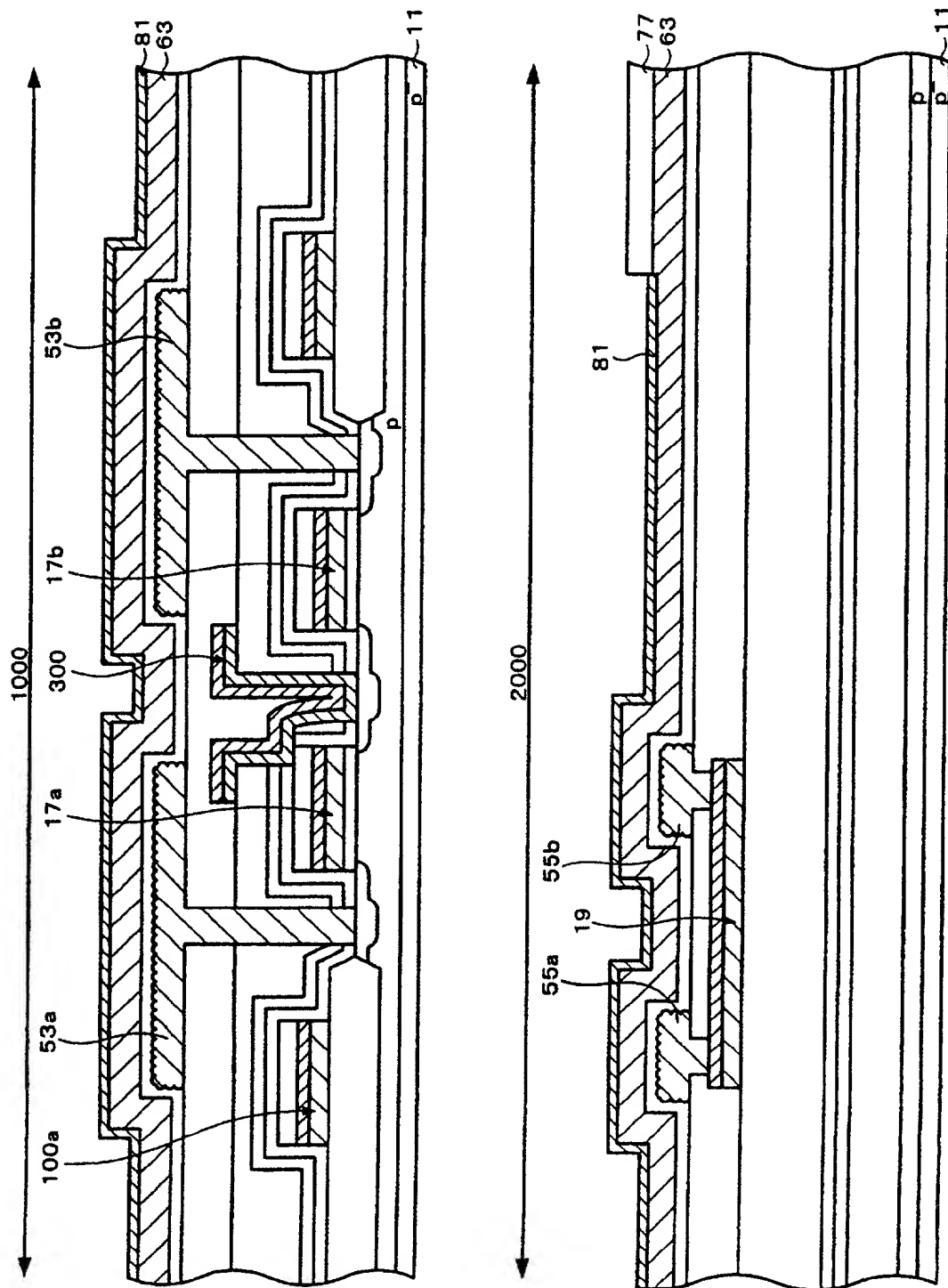


Fig. 20

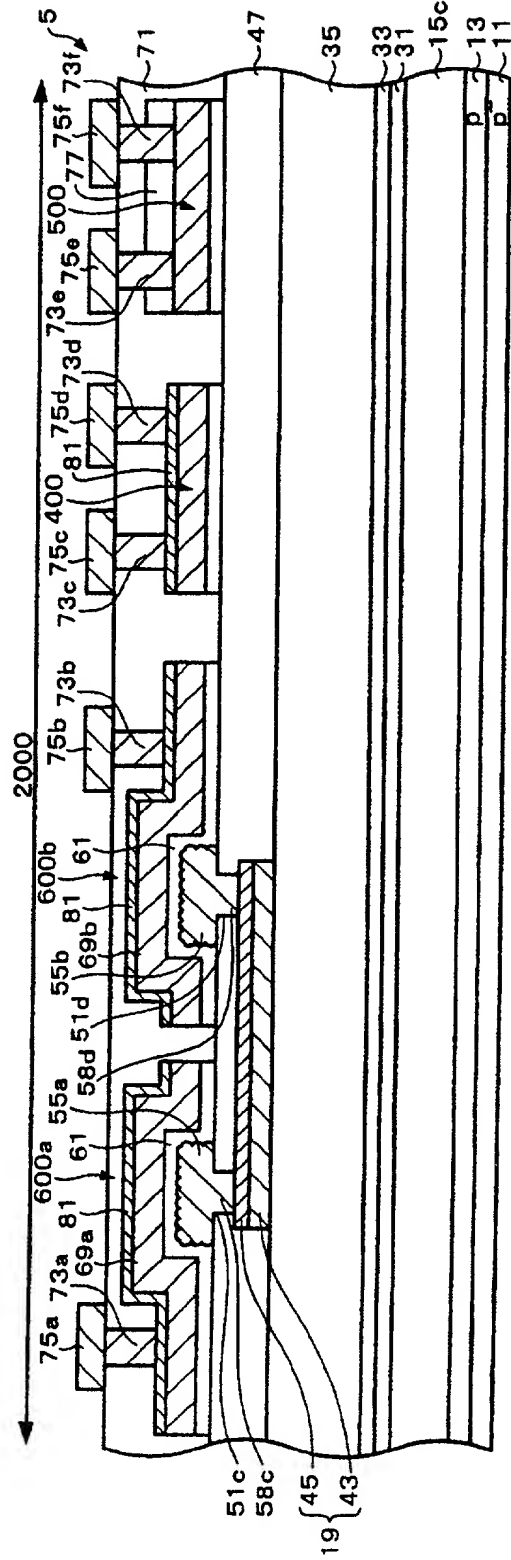
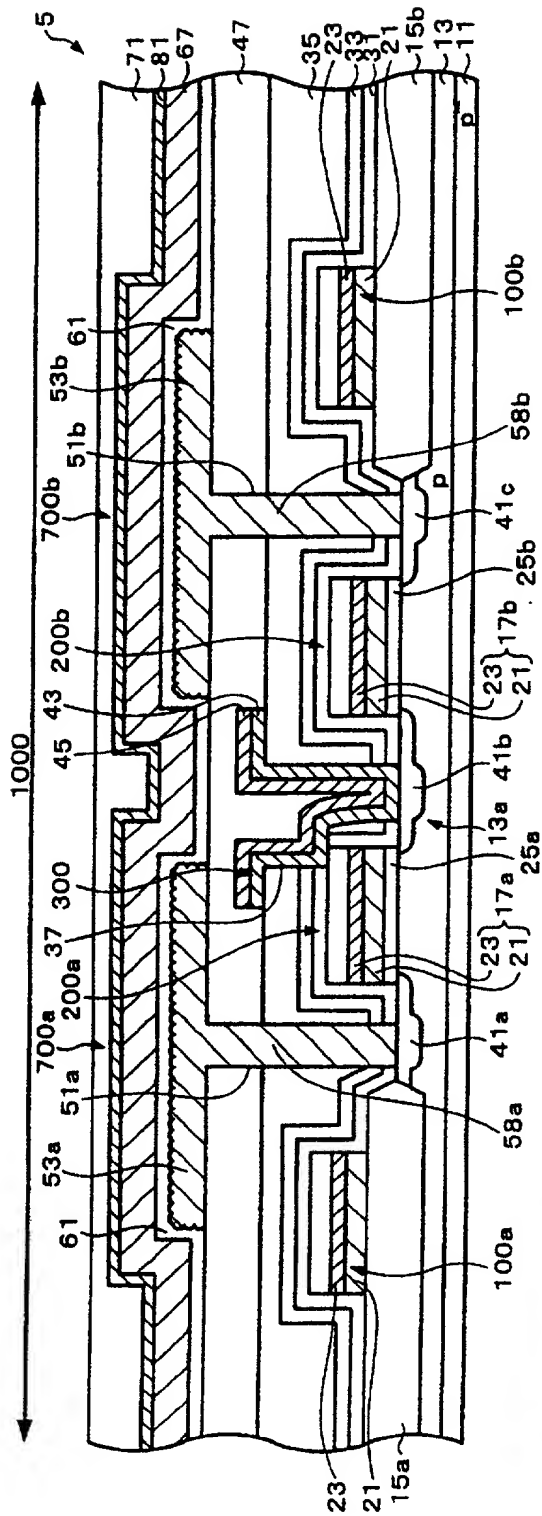


Fig. 21

